

INITIAL PRODUCT/PROCESS CHANGE NOTIFICATION #16495

Generic Copy

Issue Date: 21-July-2010

TITLE: Initial Notification of DPAK capacity expansion of some Discrete devices at Ningbo Mingxin Microelectronics Co., Ltd. and Nantong Fujitsu Microelectronics Co., Ltd.

PROPOSED FIRST SHIP DATE: 21-Nov-2010

AFFECTED CHANGE CATEGORY(S): Additional DPAK packaging sites

FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:

Contact your local ON Semiconductor Sales Office or Sean Clarksean.clark@onsemi.com

NOTIFICATION TYPE:

Initial Product/Process Change Notification (IPCN)

First change notification sent to customers. IPCNs are issued at least 120 days prior to implementation of the change. An IPCN is advance notification about an upcoming change and contains general information regarding the change details and devices affected. It also contains the preliminary reliability qualification plan.

The completed qualification and characterization data will be included in the Final Product/Process Change Notification (FPCN).

This IPCN notification will be followed by a Final Product/Process Change Notification (FPCN) at least 90 days prior to implementation of the change.

DESCRIPTION AND PURPOSE:

To meet customer demand for Standard Products in the DPAK (TO-252 and TO-251) package, ON Semiconductor is expanding capacity at two suppliers: Nantong Fujitsu and Ningbo MingXin Ltd.

ON Semiconductor Standard Products Group will also continue to utilize our facility in Seremban, Malaysia for the assembly and test of Standard Products in the DPAK package.

Nantong Fujitsu Microelectronics Co., Ltd. is a long term supplier of many packages to ON Semiconductor and is ISO9002, ISO14001 and TS16949 certified. The facility is currently used to manufacture ON Semiconductor's TO-220AB, AC, I2PAK, TO-247 and other DPAK devices. Ningbo MingXin Microelectronics Ltd. Is a supplier of power packages to many large semiconductor companies and is ISO9002, ISO14001 and TS16949 certified.

The DPAK capacity expansion of halide-free products will affect the listed Discrete devices.

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QUALIFICATION PLAN:

Qualification tests are designed to show that the reliability of transferred devices will continue to meet or exceed ON Semiconductor standards.

Estimated Date for Qualification Completion: Q3-2010 Samples should be available after completion of Qualification.

Reliability testing will be performed on qualification vehicles chosen based on die size and voltage rating. The following qualification vehicles were selected for this qualification.

MURD550PFT4G MBRD5H100T4G MJD340T4G MJD350T4G MBRD660CTT4G

RELIABILITY DATA SUMMARY:

Test: HTRB	Conditions: Ta=150C,80% Rated Voltage	Interval: 1008 hrs
PreConditioning	MSL 1 @ 260C	
Autoclave+PC	Ta=121C RH=100% ~15 psig	96 hrs
H3TRB+PC	Ta=85C RH=85% bias=80% rated V or100V Max	1008 hrs
IOL+PC	Ta=25C, Delta TJ = 100 C, Ton/off = 2 min.	15000 cyc
TC+PC	Ta= -65 C to 150 C	1000 cyc
RSH	Ta=260C, 10 sec dwell	
Solderability	Ta=245C, 10 sec dwell	

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List of affected General Parts:

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	PART		
BUD42DT4G	MJD350T4G	MBRD360G	
MJD112G	MJD41CRLG	MBRD360RLG	
MJD112RLG	MJD41CT4G	MBRD360T4G	
MJD112T4G	MJD42C1G	MBRD5H100T4G	
MJD117G	MJD42CG	MBRD620CTT4G	
MJD117RLG	MJD42CRLG	MBRD630CTT4G	
MJD117T4G	MJD42CT4G	MBRD640CTG	
MJD122G	MJD44E3T4G	MBRD640CTT4G	
MJD122T4G	MJD44H11G	MBRD640CTT4H	
MJD127G	MJD44H11RLG	MBRD650CTG	
MJD127T4G	MJD44H11T4G	MBRD650CTT4G	
MJD128T4G	MJD44H11T5G	MBRD660CTG	
MJD148T4G	MJD45H11G	MBRD660CTRLG	
MJD200G	MJD45H11RLG	MBRD660CTT4G	
MJD200RLG	MJD45H11T4G	MBRD660CTT4H	
MJD200T4G	MJD47G	MBRD835LG	
MJD200T5G	MJD47T4G	MBRD835LT4G	
MJD210G	MJD50G	MBRD835LT4H	
MJD210RLG	MJD50T4G	MSRD620CTG	
MJD210T4G	MJD5731T4G	MSRD620CTRG	
MJD243G	MJD6039T4G	MSRD620CTT4G	
MJD243T4G	NJD2873T4G	MSRD620CTT4RG	
MJD253T4G	NJD35N04G	MURD320T4G	
MJD2955G	NJD35N04T4G	MURD330T4G	
MJD2955T4G	MBRD1035CTLG	MURD340T4G	
MJD3055G	MBRD1035CTLT4G	MURD530T4G	
MJD3055T4G	MBRD1045T4G	MURD550PFT4G	
MJD31C1G	MBRD320G	MURD620CTG	
MJD31CG	MBRD320RLG	MURD620CTH	
MJD31CRLG	MBRD320RLH	MURD620CTT4G	
MJD31CT4G	MBRD320T4G	MURHD560T4G	
MJD31T4G	MBRD320T4H	MURHD560W1T4G	
MJD32CG	MBRD330G		
MJD32CRLG	MBRD330RLG		
MJD32CT4G	MBRD330T4G		
MJD32RLG	MBRD340G		
MJD32T4G	MBRD340RLG		
MJD340G	MBRD340T4G		
MJD340RLG	MBRD350G		
MJD340T4G	MBRD350RLG		
MJD350G	MBRD350T4G		

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